

FDD2570

150V N-Channel PowerTrench® MOSFET

General Description

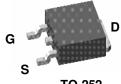
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{\text{DS(ON)}}$ specifications.

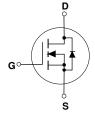
The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- 4.7 A, 150 V. $R_{DS(ON)} = 80 \ m\Omega$ @ $V_{GS} = 10 \ V$ $R_{DS(ON)} = 90 \text{ m}\Omega$ @ $V_{GS} = 6 \text{ V}$
- · Low gate charge
- · Fast switching speed
- High performance trench technology for extremely low R_{DS(ON)}
- High power and current handling capability.







Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		150	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1a)	4.7	A
	Drain Current - Pulsed		30	
P _D	Maximum Power Dissipation @ T _C = 25°C	(Note 1)	70	W
	@ T _A = 25°C	(Note 1a)	3.2	
	@ T _A = 25°C	(Note 1b)	1.3	
T_J, T_{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

R _{eJC}	Thermal Resistance, Junction-to-Case	(Note 1)	1.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

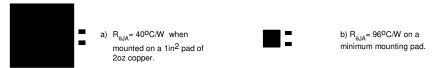
Package Marking and Ordering Information

 Device Marking	Device	Reel Size	Tape width	Quantity
FDD2570	FDD2570	13"	16mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Not	re 1)		l		
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 75 \text{ V}, \qquad I_D = 4.7 \text{ A}$			375	mJ
I _{AR}	Maximum Drain-Source Avalanche Current				4.7	Α
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	150			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		150		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 120 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}$ $V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2	2.6	4	V
$\Delta V_{GS(th)} = \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-7		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$\begin{split} &V_{GS} = 10 \ V, &I_{D} = 4.7 \ A \\ &V_{GS} = 6 \ V, &I_{D} = 4.5 \ A \\ &V_{GS} = 10 \ V, I_{D} = 4.7 \ A, T_{J} = 125 ^{\circ}C \end{split}$		60 63 120	80 90 158	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	30			Α
g FS	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_D = 6.3 \text{ A}$		20		S
Dynamic	Characteristics		-			
C _{iss}	Input Capacitance	$V_{DS} = 75 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		1907		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		117		pF
C _{rss}	Reverse Transfer Capacitance			33		pF
Switchin	ng Characteristics (Note 2)		- II	l		
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 75 \text{ V}, \qquad I_{D} = 1 \text{ A},$		12	19	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		7	14	ns
t _{d(off)}	Turn-Off Delay Time			41	65	ns
t _f	Turn-Off Fall Time			21	34	ns
Qg	Total Gate Charge	$V_{DS} = 75 \text{ V}, \qquad I_D = 4.7 \text{ A},$		39	62	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		7		nC
Q_{gd}	Gate-Drain Charge			9		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Sourc				2.7	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.7 \text{ A}$ (Note 2)		0.7	1.2	٧

Notes

R_{aJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{aJC} is guaranteed by design while R_{eCA} is determined by the user's board design.



Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300 $\mu s,$ Duty Cycle < 2.0%

Typical Characteristics

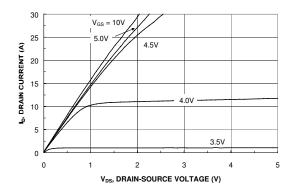
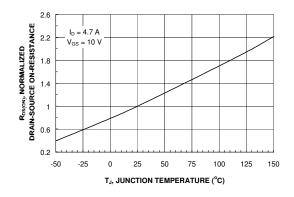


Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



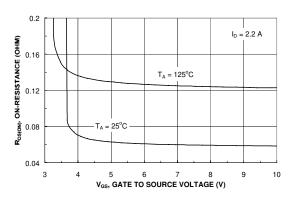
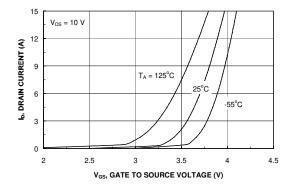


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



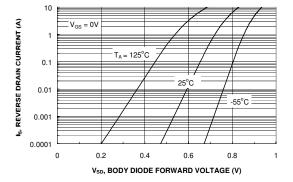
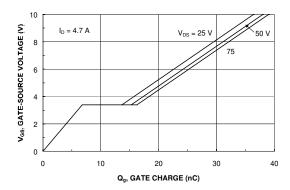


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



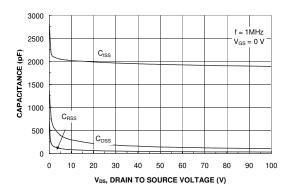


Figure 7. Gate Charge Characteristics.

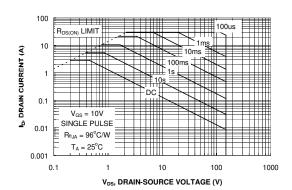


Figure 8. Capacitance Characteristics.

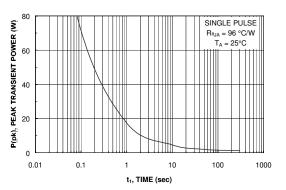


Figure 9. Maximum Safe Operating Area.



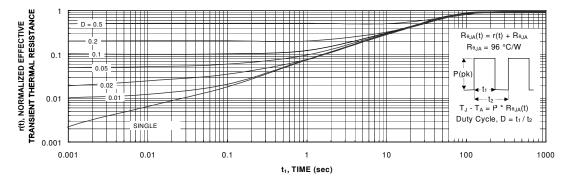


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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